Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/541,015	SCHLEUCHER, HEIKO
Examiner	Art Unit
SANG KIM	3654

SEARCHED					
Class	Subclass	Date	Examiner		
242	580 579 402 172	8/21/2007	sĸ		
24	600.9	8/21/2007	SK ,		
24	601.24	8/21/2007	SK		
24	601.79	8/21/2007	SK		
24	698.13	8/21/2007	SK		
		V			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	<u></u>				

	SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR			
John Nguyen: 242/402, 172 Dean Kramer: 294/No search	8/14/2007	sĸ			
James Brittain: 24/600.9, 601.24, 601.79, 698.13	8/21/2007	sĸ			
•					
		· · · · · · · · · · · · · · · · · · ·			